

Notice of References Cited	Application/Control No. 10/665,980	Applicant(s)/Patent Under Reexamination MIDDLEBROOKS, SCOTT A.	
	Examiner Russell Frejd	Art Unit 2128	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,551,015	11-1985	Goemans, Hermanus I.	355/75
	B	US-5,968,607	10-1999	Lovison, Douglas I.	427/511
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	ABUGHAZALEH et al., S.A. Null holographic test structures for the measurement of overlay and its statistical variation, IEEE Transactions on Semiconductor Manufacturing, Vol. 13, No. 2, May 2000, pp. 173-80.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.